

# SN5472, SN7472 AND-GATED J-K MASTER-SLAVE FLIP-FLOPS WITH PRESET AND CLEAR

SDLS117

DECEMBER 1983 — REVISED MARCH 1988

- Package Options Include Plastic and Ceramic DIPs and Ceramic Flat Packages
- Dependable Texas Instruments Quality and Reliability

## description

These J-K flip-flops are based on the master-slave principle and each has AND gate inputs for entry into the master section which are controlled by the clock pulse. The clock pulse also regulates the state of the coupling transistors which connect the master and slave sections. The sequence of operation is as follows:

1. Isolate slave from master
2. Enter information from AND gate inputs to master
3. Disable AND gate inputs
4. Transfer information from master to slave

The logical states of the J and K inputs must not be allowed to change when the clock pulse is in a high state.

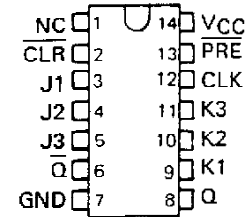
The SN5472, and the SN54H72 are characterized for operation over the full military temperature range of -55°C to 125°C. The SN7472 is characterized for operation from 0°C to 70°C.

FUNCTION TABLE

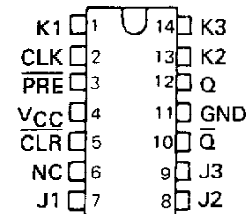
INPUTS					OUTPUTS	
PRE	CLR	CLK	J	K	Q	$\bar{Q}$
L	H	X	X	X	H	L
H	L	X	X	X	L	H
L	L	X	X	X	H <sup>†</sup>	H <sup>†</sup>
H	H	$\downarrow$	L	L	Q <sub>0</sub>	$\bar{Q}_0$
H	H	$\downarrow$	H	L	H	L
H	H	$\downarrow$	L	H	L	H
H	H	$\downarrow$	H	H	TOGGLE	TOGGLE

<sup>†</sup> This configuration is nonstable; that is, it will not persist when either preset or clear returns to its inactive (high) level.

SN5472 . . . J PACKAGE  
SN7472 . . . N PACKAGE  
(TOP VIEW)

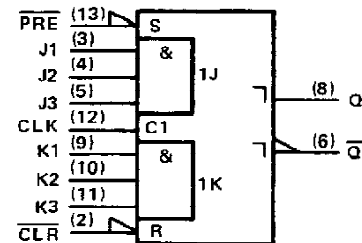


SN5472 . . . W PACKAGE  
(TOP VIEW)



NC - No internal connection

## logic symbol<sup>‡</sup>



<sup>‡</sup> This symbol is in accordance with ANSI/IEEE Std. 91-1984 and IEC Publication 617-12.

Pin numbers shown are for J and N packages.

## positive logic

$$J = J1 \cdot J2 \cdot J3$$

$$K = K1 \cdot K2 \cdot K3$$

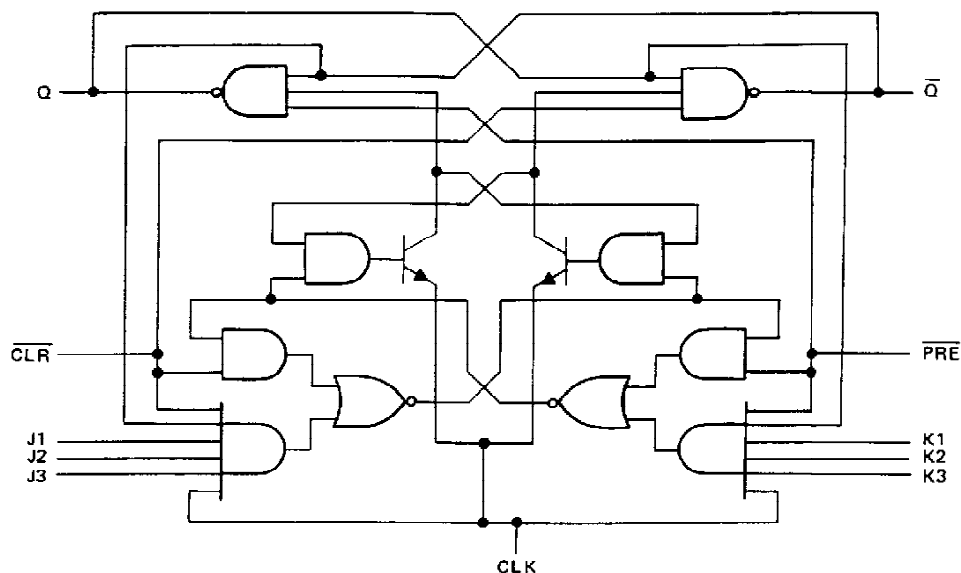
PRODUCTION DATA documents contain information current as of publication date. Products conform to specifications per the terms of Texas Instruments standard warranty. Production processing does not necessarily include testing of all parameters.

TEXAS  
INSTRUMENTS

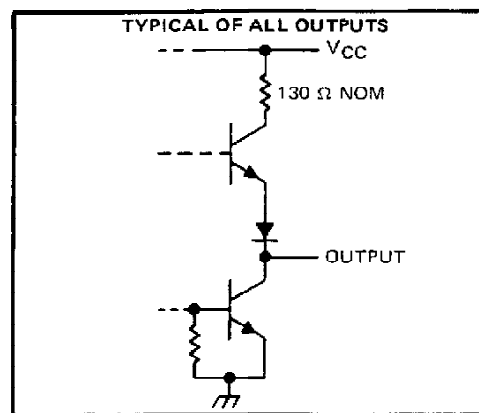
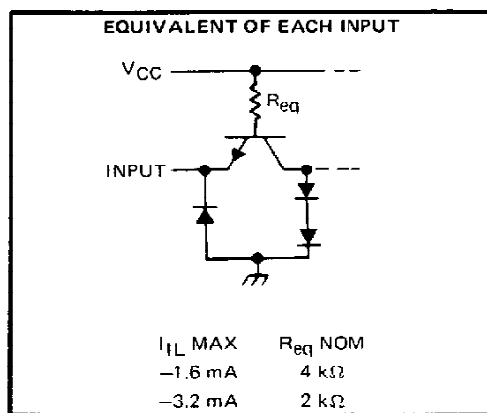
POST OFFICE BOX 655012 • DALLAS, TEXAS 75265

# **SN5472, SN7472** **AND-GATED J-K MASTER-SLAVE FLIP-FLOPS WITH PRESET AND CLEAR**

logic diagram (positive logic)



schematics of inputs and outputs



absolute maximum ratings over operating free-air temperature range (unless otherwise noted)

Supply voltage, $V_{CC}$ (see Note 1)	7 V
Input voltage	5.5 V
Operating free-air temperature: SN54'	-55°C to 125°C
SN74'	0°C to 70°C
Storage temperature range	-65°C to 150°C

NOTE 1: Voltage values are with respect to network ground terminal.

**TEXAS**  
**INSTRUMENTS**

POST OFFICE BOX 655012 • DALLAS, TEXAS 75265

# SN5472, SN7472

## AND-GATED J-K MASTER-SLAVE FLIP-FLOPS WITH PRESET AND CLEAR

### recommended operating conditions

		SN5472			SN7472			UNIT
		MIN	NOM	MAX	MIN	NOM	MAX	
V <sub>CC</sub>	Supply voltage	4.5	5	5.5	4.75	5	5.25	V
V <sub>IH</sub>	High-level input voltage	2			2			V
V <sub>IL</sub>	Low-level input voltage			0.8			0.8	V
I <sub>OH</sub>	High-level output current			− 0.4			− 0.4	mA
I <sub>OL</sub>	Low-level output current			16			16	mA
t <sub>w</sub>	Pulse duration	CLK high		20	20		ns	
		CLK low		47	47			
		PRE or CLR		25	25			
t <sub>su</sub>	Input setup time before CLK ↑	0		0	0		ns	
t <sub>h</sub>	Input hold time-data after CLK ↓	0		0	0		ns	
T <sub>A</sub>	Operating free-air temperature	− 55		125	0		70	°C

### electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST CONDITIONS $\dagger$		SN5472			SN7472			UNIT
				MIN	TYP $\ddagger$	MAX	MIN	TYP $\ddagger$	MAX	
$V_{IK}$		$V_{CC} = \text{MIN}, I_I = -12 \text{ mA}$				-1.5			-1.5	V
$V_{OH}$		$V_{CC} = \text{MIN}, V_{IH} = 2 \text{ V}, V_{IL} = 0.8 \text{ V}, I_{OH} = -0.4 \text{ mA}$		2.4	3.4		2.4	3.4		V
$V_{OL}$		$V_{CC} = \text{MIN}, V_{IH} = 2 \text{ V}, V_{IL} = 0.8 \text{ V}, I_{OL} = 16 \text{ mA}$			0.2	0.4		0.2	0.4	V
$I_I$		$V_{CC} = \text{MAX}, V_I = 5.5 \text{ V}$			1			1		mA
$I_{IH}$	J or K	$V_{CC} = \text{MAX}, V_I = 2.4 \text{ V}$			40			40		$\mu\text{A}$
	All other				80			80		
$I_{IL}$	J or K	$V_{CC} = \text{MAX}, V_I = 0.4 \text{ V}$			-1.6			-1.6		mA
	All other				-3.2			-3.2		
$I_{OS}\S$		$V_{CC} = \text{MAX}$		-20		-57	-18		-57	mA
$I_{CC}$		$V_{CC} = \text{MAX}, \text{ See Note 2}$			10	20		10	20	mA

$\dagger$  For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.

$\ddagger$  All typical values are at  $V_{CC} = 5 \text{ V}, T_A = 25^{\circ}\text{C}$ .

$\S$  Not more than one output should be shorted at a time.

NOTE 2: With all outputs open,  $I_{CC}$  is measured with the Q and  $\bar{Q}$  outputs high in turn. At the time of measurement, the clock input is grounded.

### switching characteristics, $V_{CC} = 5 \text{ V}, T_A = 25^{\circ}\text{C}$ (see note 3)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	TEST CONDITIONS	MIN	TYP	MAX	UNIT
$f_{\max}$			$R_L = 400\ \Omega,$ $C_L = 15\ \text{pF}$	15	20		MHz
$t_{\text{PLH}}$	$\overline{\text{PRE}}$ or $\overline{\text{CLR}}$	$Q$ or $\overline{Q}$			16	25	ns
$t_{\text{PHL}}$					25	40	ns
$t_{\text{PLH}}$	CLK	$Q$ or $\overline{Q}$			16	25	ns
$t_{\text{PHL}}$					25	40	ns

NOTE 3: Load circuits and voltage waveforms are shown in Section 1.

TEXAS  
INSTRUMENTS

POST OFFICE BOX 655012 • DALLAS, TEXAS 75265

## IMPORTANT NOTICE

Texas Instruments (TI) reserves the right to make changes to its products or to discontinue any semiconductor product or service without notice, and advises its customers to obtain the latest version of relevant information to verify, before placing orders, that the information being relied on is current.

TI warrants performance of its semiconductor products and related software to the specifications applicable at the time of sale in accordance with TI's standard warranty. Testing and other quality control techniques are utilized to the extent TI deems necessary to support this warranty. Specific testing of all parameters of each device is not necessarily performed, except those mandated by government requirements.

Certain applications using semiconductor products may involve potential risks of death, personal injury, or severe property or environmental damage ("Critical Applications").

TI SEMICONDUCTOR PRODUCTS ARE NOT DESIGNED, INTENDED, AUTHORIZED, OR WARRANTED TO BE SUITABLE FOR USE IN LIFE-SUPPORT APPLICATIONS, DEVICES OR SYSTEMS OR OTHER CRITICAL APPLICATIONS.

Inclusion of TI products in such applications is understood to be fully at the risk of the customer. Use of TI products in such applications requires the written approval of an appropriate TI officer. Questions concerning potential risk applications should be directed to TI through a local SC sales office.

In order to minimize risks associated with the customer's applications, adequate design and operating safeguards should be provided by the customer to minimize inherent or procedural hazards.

TI assumes no liability for applications assistance, customer product design, software performance, or infringement of patents or services described herein. Nor does TI warrant or represent that any license, either express or implied, is granted under any patent right, copyright, mask work right, or other intellectual property right of TI covering or relating to any combination, machine, or process in which such semiconductor products or services might be or are used.

## **IMPORTANT NOTICE**

Texas Instruments and its subsidiaries (TI) reserve the right to make changes to their products or to discontinue any product or service without notice, and advise customers to obtain the latest version of relevant information to verify, before placing orders, that information being relied on is current and complete. All products are sold subject to the terms and conditions of sale supplied at the time of order acknowledgement, including those pertaining to warranty, patent infringement, and limitation of liability.

TI warrants performance of its semiconductor products to the specifications applicable at the time of sale in accordance with TI's standard warranty. Testing and other quality control techniques are utilized to the extent TI deems necessary to support this warranty. Specific testing of all parameters of each device is not necessarily performed, except those mandated by government requirements.

CERTAIN APPLICATIONS USING SEMICONDUCTOR PRODUCTS MAY INVOLVE POTENTIAL RISKS OF DEATH, PERSONAL INJURY, OR SEVERE PROPERTY OR ENVIRONMENTAL DAMAGE ("CRITICAL APPLICATIONS"). TI SEMICONDUCTOR PRODUCTS ARE NOT DESIGNED, AUTHORIZED, OR WARRANTED TO BE SUITABLE FOR USE IN LIFE-SUPPORT DEVICES OR SYSTEMS OR OTHER CRITICAL APPLICATIONS. INCLUSION OF TI PRODUCTS IN SUCH APPLICATIONS IS UNDERSTOOD TO BE FULLY AT THE CUSTOMER'S RISK.

In order to minimize risks associated with the customer's applications, adequate design and operating safeguards must be provided by the customer to minimize inherent or procedural hazards.

TI assumes no liability for applications assistance or customer product design. TI does not warrant or represent that any license, either express or implied, is granted under any patent right, copyright, mask work right, or other intellectual property right of TI covering or relating to any combination, machine, or process in which such semiconductor products or services might be or are used. TI's publication of information regarding any third party's products or services does not constitute TI's approval, warranty or endorsement thereof.